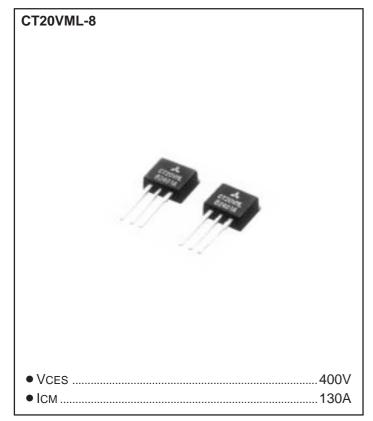
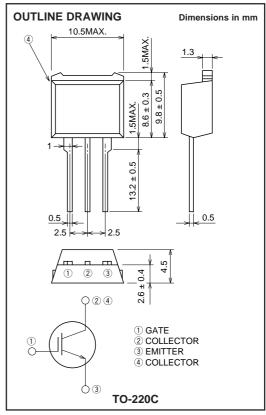
## MITSUBISHI INSULATED GATE BIPOLAR TRANSISTOR

# CT20VML-8

STROBE FLASHER USE





# **APPLICATION**

Strobe Flasher.

### MAXIMUM RATINGS (Tc = 25°C)

Symbol	Parameter	Conditions	Ratings	Unit
VCES	Collector-emitter voltage	VGE = 0V	400	V
VGES	Gate-emitter voltage	VCE = 0V, See notice 4	±15	V
VGEM	Peak gate-emitter voltage	VCE = 0V, tw = 10s	±16	V
Ісм	Collector current (Pulsed)	See figure 1	130	Α
Tj	Junction temperature		-40 ~ <b>+</b> 150	°C
Tstg	Storage temperature		-40 ~ <b>+</b> 150	°C

### **ELECTRICAL CHARACTERISTICS** (Tj = 25°C)

Symbol	Parameter	Test conditions	Limits			Unit
			Min.	Тур.	Max.	Offic
V(BR)CES	Collector-emitter breakdown voltage	IC = 1mA, VGE = 0V	450	_	_	V
ICES	Collector-emitter leakage current	VCE = 400V, VGE = 0V	_	_	10	μΑ
IGES	Gate-emitter leakage current	VGE = ±16V, VCE = 0V	_	_	±0.1	μΑ
VGE(th)	Gate-emitter threshold voltage	VCE = 10V, IC = 1mA	0.5	_	2.0	V



Feb.1999

# CT20VML-8

### STROBE FLASHER USE

### **PERFORMANCE CURVES**

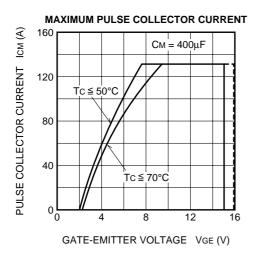
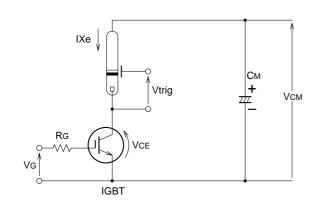
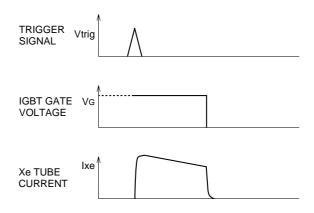


Figure 1

### **APPLICATION EXAMPLE**





#### RECOMMEND CONDITION MAXIMUM CONDITION

VcM = 330V	350V
IP = 120A	130A
$CM = 300 \mu F$	400μF
VGE = 12V	·

Notice 1. Gate drive voltage during on-period must be applied to satisfy the rating of maximum pulse collector current. And reverse gate current during turn-off must be kept less than 0.5A. (In general, it is satisfied if  $Rg \ge 47\Omega$ )

Notice 2. IGBT has MOS structure and its gate is insulated by thin silicon oxide. So please handle carefully not to suffer from electrostatic charge.

Notice 3. The operation life should be endured 5,000 shots under the charge current (Ixe  $\leq 130A$ : full luminescence condition) of main condenser (CM=400 $\mu$ F). Repetition period under full luminescence condition is over 3 seconds.

Notice 4. Total operation hours must be applied within 5,000 hours.

